

**A METHOD OF SAMPLE PREPARATION FOR ATOM PROBES
AND SOURCE OF SPECIMENS**

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Abstract of the Disclosure

A specimen for atom probe analysis is prepared by providing a slab of material from which the specimen will be taken; defining a plurality of posts in the slab by in the slab; removing at least one post from the slab; and mounting the post. The post is shaped to a tip shape suitable for use in the atom probe, such as by focused ion beam milling the post to a tip shape. Grooves are cross cut into the slab. If needed, each groove is filled with a supporting material prior to cutting a parallel or intersecting groove thereto. The invention is also defined as a source of specimens for use in atom probe sampling comprising a slab of material from which the specimen will be taken, which has been defined into a plurality of posts and from which slab at least one post is removed from the slab and mounted.